Jameco Part Number 301233

SN54LS138, SN54S138, SN74LS138, SN74S138A
3-LINE TO 8-LINE DECODERS/DEMULTIPLEXERS

SDLS014

DECEMBER 1972—REVISED MARCH 1988

- **Designed Specifically for High-Speed:**
  Memory Decoders
  Data Transmission Systems
- **3 Enable Inputs to Simplify Cascading and/or Data Reception**
- **Schottky-Clamped for High Performance**

description

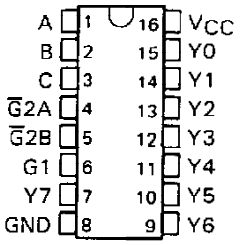
These Schottky-clamped TTL MSI circuits are designed to be used in high-performance memory decoding or data-routing applications requiring very short propagation delay times. In high-performance memory systems, these docoders can be used to minimize the effects of system decoding. When employed with high-speed memories utilizing a fast enable circuit, the delay times of these decoders and the enable time of the memory are usually less than the typical access time of the memory. This means that the effective system delay introduced by the Schottky-clamped system decoder is negligible.

The 'LS138, SN54S138, and SN74S138A decode one of eight lines dependent on the conditions at the three binary select inputs and the three enable inputs. Two active-low and one active-high enable inputs reduce the need for external gates or inverters when expanding. A 24-line decoder can be implemented without external inverters and a 32-line decoder requires only one inverter. An enable input can be used as a data input for demultiplexing applications.

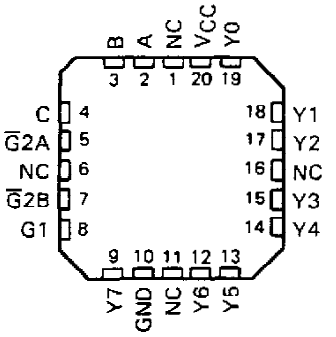
All of these decoder/demultiplexers feature fully buffered inputs, each of which represents only one normalized load to its driving circuit. All inputs are clamped with high-performance Schottky diodes to suppress line-ringing and to simplify system design.

The SN54LS138 and SN54S138 are characterized for operation over the full military temperature range of −55°C to 125°C. The SN74LS138 and SN74S138A are characterized for operation from 0°C to 70°C.

SN54LS138, SN54S138 . . . J OR W PACKAGE
SN74LS138, SN74S138A . . . D OR N PACKAGE
(TOP VIEW)

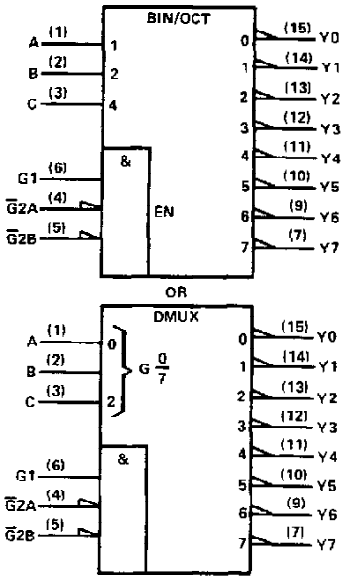


SN54LS138, SN54S138 . . . FK PACKAGE
(TOP VIEW)



NC—No internal connection

logic symbols†



†These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for D, J, N, and W packages.

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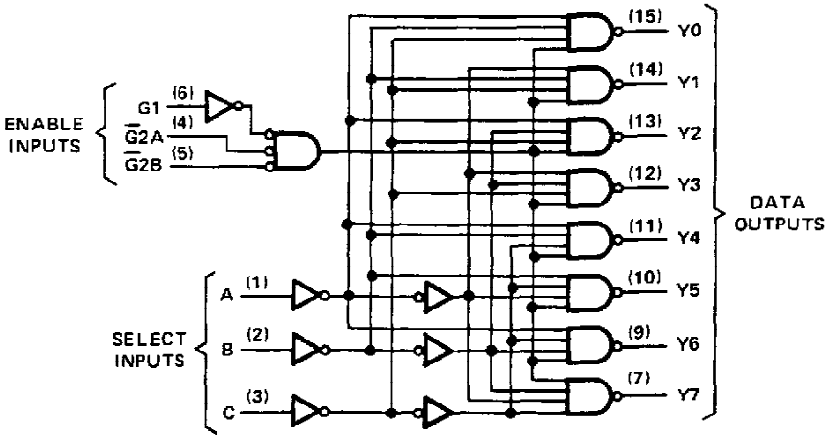
logic diagram and function table

'LS138, SN54S138, SN74S138A



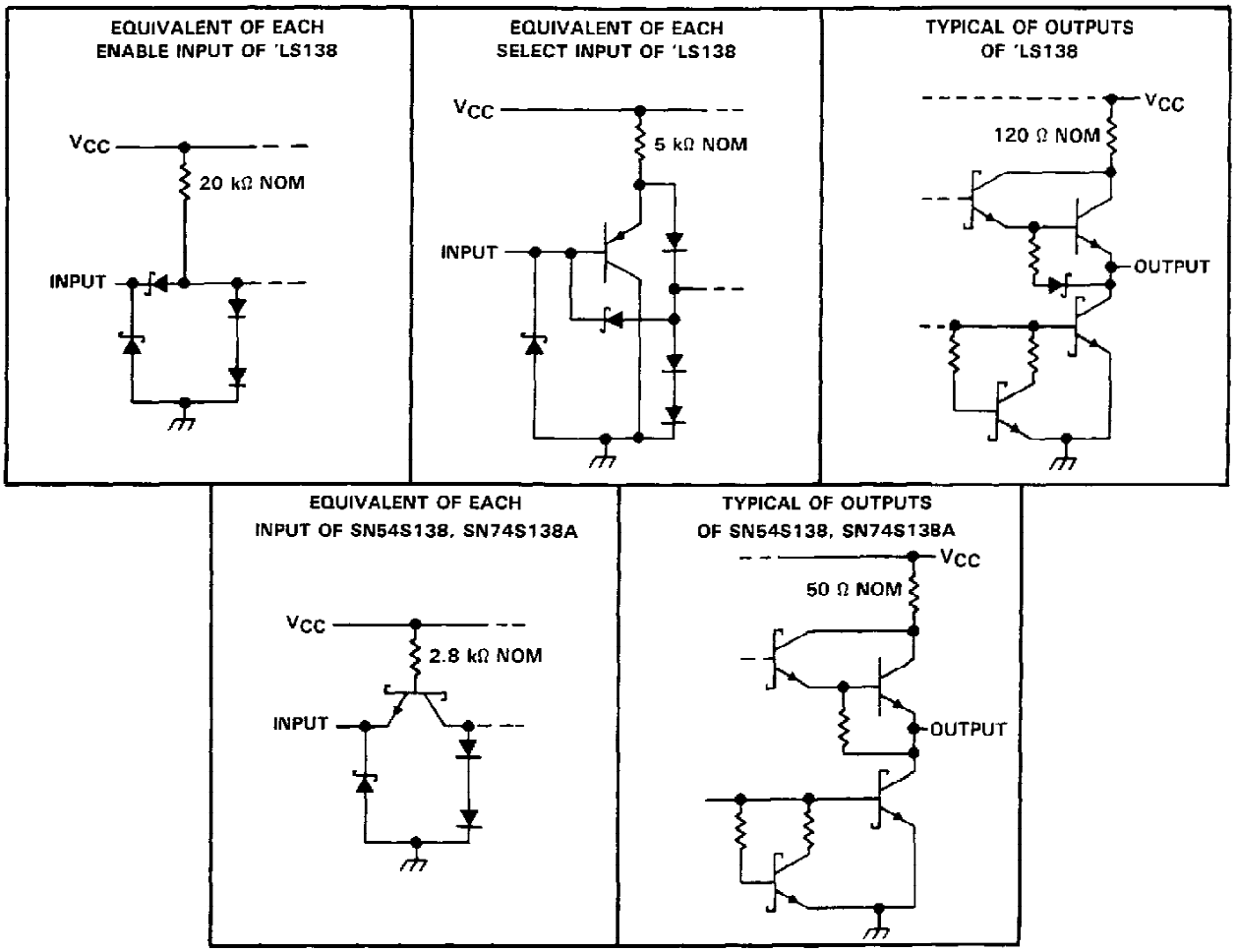
Pin numbers shown are for D, J, N, and W packages.

'LS138, SN54138, SN74S138A
FUNCTION TABLE

INPUTS					OUTPUTS							
ENABLE		SELECT										
G1	$\overline{G2}$*	C	B	A	Y0	Y1	Y2	Y3	Y4	Y5	Y6	Y7
X	H	X	X	X	H	H	H	H	H	H	H	H
L	X	X	X	X	H	H	H	H	H	H	H	H
H	L	L	L	L	L	H	H	H	H	H	H	H
H	L	L	L	H	H	L	H	H	H	H	H	H
H	L	L	H	L	H	H	L	H	H	H	H	H
H	L	L	H	H	H	H	H	L	H	H	H	H
H	L	H	L	L	H	H	H	H	L	H	H	H
H	L	H	L	H	H	H	H	H	H	L	H	H
H	L	H	H	L	H	H	H	H	H	H	L	H
H	L	H	H	H	H	H	H	H	H	H	H	L

*$\overline{G2} = \overline{G2A} + \overline{G2B}$
H = high level, L = low level, X = irrelevant

schematics of inputs and outputs



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1) . . . . . 7 V
Input voltage . . . . . 7 V
Operating free-air temperature range: SN54LS138, SN54S138 . . . . . −55°C to 125°C
SN74LS138, SN74S138A . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		SN54LS138			SN74LS138			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.7			0.8	V
I_{OH}	High-level output current			−0.4			−0.4	mA
I_{OL}	Low-level output current			4			8	mA
T_A	Operating free-air temperature	−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†		SN54LS138			SN74LS138			UNIT
			MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IK}	V_{CC} = MIN, I_I = −18 mA				−1.5			−1.5	V
V_{OH}	V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = MAX, I_{OH} = −0.4 mA		2.5	3.4		2.7	3.4		V
V_{OL}	V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = MAX	I_{OL} = 4 mA		0.25	0.4		0.25	0.4	V
		I_{OL} = 8 mA					0.35	0.5	
I_I	V_{CC} = MAX, V_I = 7 V				0.1			0.1	mA
I_{IH}	V_{CC} = MAX, V_I = 2.7 V				20			20	μA
I_{IL}	V_{CC} = MAX, V_I = 0.4 V	Enable			−0.4			−0.4	mA
		A, B, C			−0.2			−0.2	
I_{OS}§	V_{CC} = MAX		−20		100	−20		−100	mA
I_{CC}	V_{CC} = MAX, Outputs enabled and open			6.3	10		6.3	10	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.
§ Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed one second.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER¶	FROM (INPUT)	TO (OUTPUT)	LEVELS OF DELAY	TEST CONDITIONS	SN54LS138 SN74LS138			UNIT
					MIN	TYP	MAX	
t_{PLH}	Binary Select	Any	2	R_L = 2 kΩ, C_L = 15 pF, See Note 2		11	20	ns
t_{PHL}						18	41	ns
t_{PLH}			3			21	27	ns
t_{PHL}						20	39	ns
t_{PLH}	Enable	Any	2			12	18	ns
t_{PHL}						20	32	ns
t_{PLH}			3			14	26	ns
t_{PHL}						13	38	ns

¶ t_{PLH} = propagation delay time, low-to-high-level ouput
t_{PHL} = propagation delay time, high-to-low-level output
NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1) . . . . . 7 V
Input voltage . . . . . 5.5 V
Operating free-air temperature range: SN54S138 . . . . . −55°C to 125°C
SN74S138A . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		SN54S138			SN74S138A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.8			0.8	V
I_{OH}	High-level output current			−1			−1	mA
I_{OL}	Low-level output current			20			20	mA
T_A	Operating free-air temperature	−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†		SN54S138 SN74S138A			UNIT
			MIN	TYP‡	MAX	
V_{IK}	V_{CC} = MIN, I_I = −18 mA				−1.2	V
V_{OH}	V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = 0.8 V, I_{OH} = −1 mA	SN54S'	2.5	3.4		V
		SN74S'	2.7	3.4		
V_{OL}	V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = 0.8 V, I_{OL} = 20 mA				0.5	V
I_I	V_{CC} = MAX, V_I = 5.5 V				1	mA
I_{IH}	V_{CC} = MAX, V_I = 2.7 V				50	μA
I_{IL}	V_{CC} = MAX, V_I = 0.5 V				−2	mA
I_{OS}§	V_{CC} = MAX		−40		−100	mA
I_{CC}	V_{CC} = MAX, Outputs enabled and open			49	74	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.
§ Not more than one output should be shorted at a time, and duration of the short circuit test should not exceed one second.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER†	FROM (INPUT)	TO (OUTPUT)	LEVELS OF DELAY	TEST CONDITIONS	SN54S138 SN74S138A			UNIT
					MIN	TYP	MAX	
t_{PLH}	Binary Select	Any	2	R_L = 280 Ω, C_L = 15 pF, See Note 2		4.5	7	ns
t_{PHL}						7	10.5	ns
t_{PLH}			3			7.5	12	ns
t_{PHL}						8	12	ns
t_{PLH}	Enable	Any	2			5	8	ns
t_{PHL}						7	11	ns
t_{PLH}			3			7	11	ns
t_{PHL}						7	11	ns

†t_{PLH} = propagation delay time, low-to-high-level output
t_{PHL} = propagation delay time, high-to-low-level output
NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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